TOK 9750 - Test Probe

2,54 mm / 100 mil

Dimensions (mm)



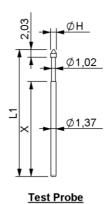
Test probes are available with different head styles. Deviating head styles are available on special request.

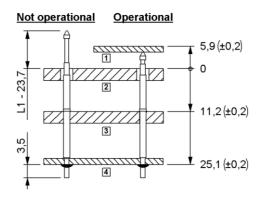
These probes are available in two different lengths, allowing for adapting the height of the probe in respect to the solder end of the component to be tested.

Deviating spring forces are also available on special request.

Please note:

When implementing more than 200N worth of test probes in a module, we strongly advise the use of one or more **TOK 9830 – Beams** (see p 81).





- 1 PCB (UUT): 1,55 4
- 2 Positioning board: 3,0 (+0,2/-0)
- 3 Spacer board: 3,0 (+0,2/-0)
- 4 Connector board: 1,55 (±0,05)

Technical Data

Spacing	2,54 mm / 100 mil 200 g	
Spring force at working level		
Current rating	3,0 A	
Typical contact resistance	14 mΩ	
Full travel	6,35 mm	
Recommended working travel	4,32 mm	
Shaft length	See "Lengths" paragraph below	

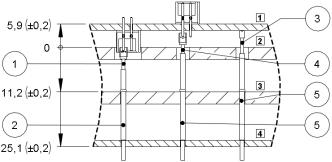
Materials

Pin barrel	Brass, gold plated	Brass, gold plated		
Pin spring	Pin spring Spring steel, gold plated			
Pin plunger	Hardened beryllium copper			

Lengths

The various lengths of the test probes are appropriate for differing situations:

L1	Х	Suitable for contacting of	
26.3 mm	17.7 mm	headers on the UUT	
30.2 mm	21.8 mm	through hole components on the UUT	
33.3 mm	24.9 mm	the UUT itself as well as the pads of SMD components	



Legend

- 1. TOK 9750-P-08-200-26.3
- 2. TOK 9750-R-01-5.6-21.3
- 3. TOK 9750-P-01-200-33.3
- 4. TOK 9750-P-08-200-30.25. TOK 9750-R-01-9.5-26.9

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Module Materials - Probes & Receptacles

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Type		Dim. ØH	Application		Length(s)
01	16 point serrated	1,52 mm		Lands, pads, leads, terminals.	26.3 mm 30.2 mm
02	6 fluted star	1,52 mm		Plated through holes, pads, lands.	33.3 mm
03	concave	1,52 mm		Long leads terminal, wire wrap pads.	26.3 mm 30.2 mm
04	conic head 30°	1,02 mm		Cuts oxidation and contamination.	33.3 mm
05	4 point crown	1,52 mm		Test pads, leads, solder points.	26.3 mm 30.2 mm
06	round	1,02 mm		Gold edge fingers, plated through holes. Leaves no marks.	33.3 mm
07	3 point crown	1,02 mm		Suitable for SMD testing due to smaller head	26.3 mm 30.2 mm
08	9 point serrated with isolation sleeve	2,23 mm	connection	Lands, pads, leads, terminals. The probe within the isolation sleeve will not make an electrical connection if no lead is present. Additionally, the isolation sleeve prevents accidental interference between probes.	26.3 mm 30.2 mm
09	6 fluted star	1,02 mm		Plated through holes, pads, lands.	33.3 mm
10	9 point serrated thin	0,60 mm		Small pads (1,2-1,5 mm), small pads with solder.	33.3 mm

^{*} Other lengths can be produced on request

How to order

All specifications are subject to change without prior notice. Consult TEST-OK for latest specifications.